

FORM PTO-1449 U.S. Department of Commerce
Patent and Trademark Office
Attorney Docket Number
 5308-168

Serial No.
 09/878,442

LIST OF DOCUMENTS CITED BY APPLICANT

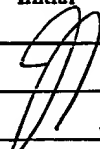
(Use several sheets if necessary)

Applicants: Das et al.

Filing Date: June 11, 2001

Group
 2815

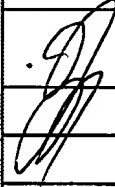
U. S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
	1	5,587,870	12/24/96	Anderson et al.	361	313

FOREIGN PATENT DOCUMENTS

Document Number	Date	Country	Class	Subclass	Translation Yes No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	2	Wang et al. "High Temperature Characteristics of High-Quality SiC MIS Capacitors with O/N/O Gate Dielectric," <i>IEEE Transactions on Electron Devices</i> . Vol. 47, No. 2, February 2000.
	3	Invitation to Pay Additional Fees for PCT/US02/09393 dated 7/7/03. ✓

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Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

11/03